

EC103D1

Sensitive gate thyristor

Rev. 01 — 1 November 2001

Product data

1. Description

Very sensitive gate thyristor intended to be interfaced directly to low power gate trigger circuits, with very low drive current capability.

Product availability:

EC103D1 in SOT54 (TO-92).

2. Features

- Blocking voltage to 400 V
- On-state RMS current to 0.8 A
- Ultra low gate trigger current
- Low cost package.

3. Applications

- Earth leakage circuit breakers
- Solid state relays
- General purpose switching.

4. Pinning information

Table 1: Pinning - SOT54 (TO-92), simplified outline and symbol

Pin	Description	Simplified outline	Symbol
1	anode (a)		
2	gate (g)		
3	cathode (k)		

SOT54 (TO-92)

5. Quick reference data

Table 2: Quick reference data

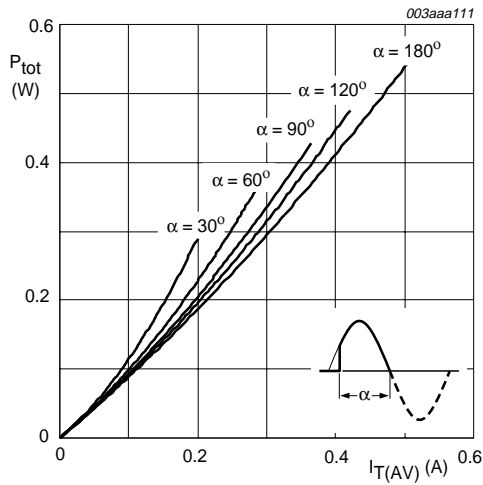
Symbol	Parameter	Conditions	Typ	Max	Unit
V_{DRM}	repetitive peak off-state voltage	$25\text{ °C} \leq T_j \leq 125\text{ °C}$	-	400	V
V_{RRM}	repetitive peak reverse voltage		-	400	V
$I_{T(RMS)}$	on-state current (RMS value)		-	0.8	A
I_{TSM}	non-repetitive peak on-state current		-	8.0	A

6. Limiting values

Table 3: Limiting values

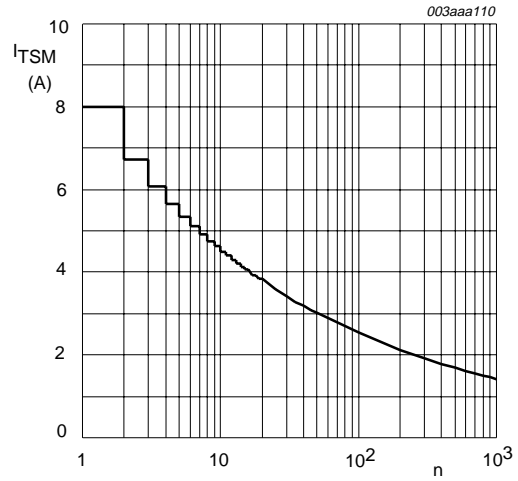
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage	$25\text{ °C} \leq T_j \leq 125\text{ °C}$	-	400	V
V_{RRM}	repetitive peak reverse voltage		-	400	V
$I_{T(AV)}$	average on-state current	half sine wave; $T_{lead} \leq 83\text{ °C}$	-	0.5	A
$I_{T(RMS)}$	on-state current (RMS value)	all conduction angles	-	0.8	A
I_{TSM}	non-repetitive peak on-state current	half sine wave; $T_j = 25\text{ °C}$ prior to surge			
		$t = 10\text{ ms}$	-	8.0	A
		$t = 8.3\text{ ms}$	-	9.0	A
I^2t	I^2t for fusing	$t = 10\text{ ms}$	-	0.32	A^2s
di_T/dt	rate of rise on-state current	$I_{TM} = 2.0\text{ A}$; $I_G = 10\text{ mA}$; $di_G/dt = 100\text{ mA}/\mu s$	-	50	$A/\mu s$
I_{GM}	peak gate current		-	1.0	A
V_{GM}	peak gate voltage		-	5.0	V
V_{RGM}	peak reverse gate voltage		-	5.0	V
P_{GM}	peak gate power		-	2.0	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.1	W
T_{stg}	storage temperature		-40	+150	$^{\circ}C$
T_j	operating junction temperature		-	+125	$^{\circ}C$



α = conduction angle

Fig 1. Maximum on-state dissipation as a function of average on-state current; typical values.



n = number of cycles at $f = 50$ Hz

Fig 2. Maximum permissible non-repetitive peak on-state current as a function of number of cycles for sinusoidal currents; typical values.

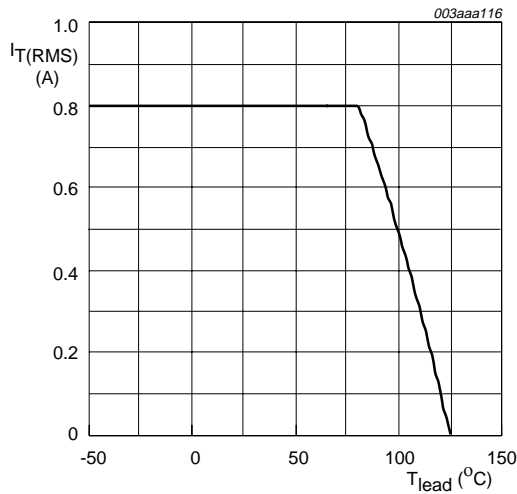
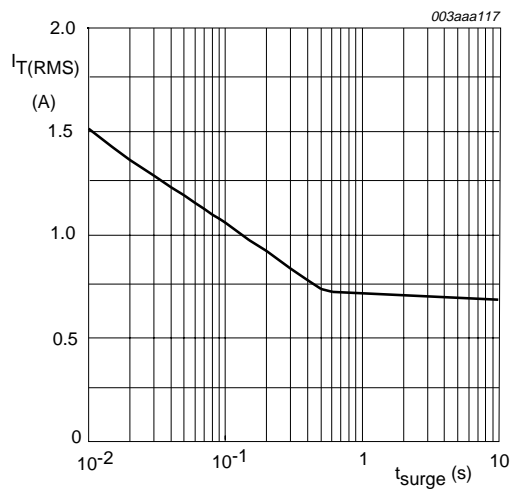


Fig 3. Maximum permissible on-state current (RMS value) as a function of lead temperature; typical values.



$f = 50$ Hz; $T_{lead} \leq 83^\circ\text{C}$.

Fig 4. Maximum permissible repetitive on-state current (RMS value) as a function of surge duration for sinusoidal currents; typical values.

7. Thermal characteristics

Table 4: Thermal characteristics

Symbol	Parameter	Conditions	Value	Unit
$R_{th(j-lead)}$	thermal resistance from junction to lead		80	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on a printed circuit board; lead length = 4 mm	150	K/W

7.1 Transient thermal impedance

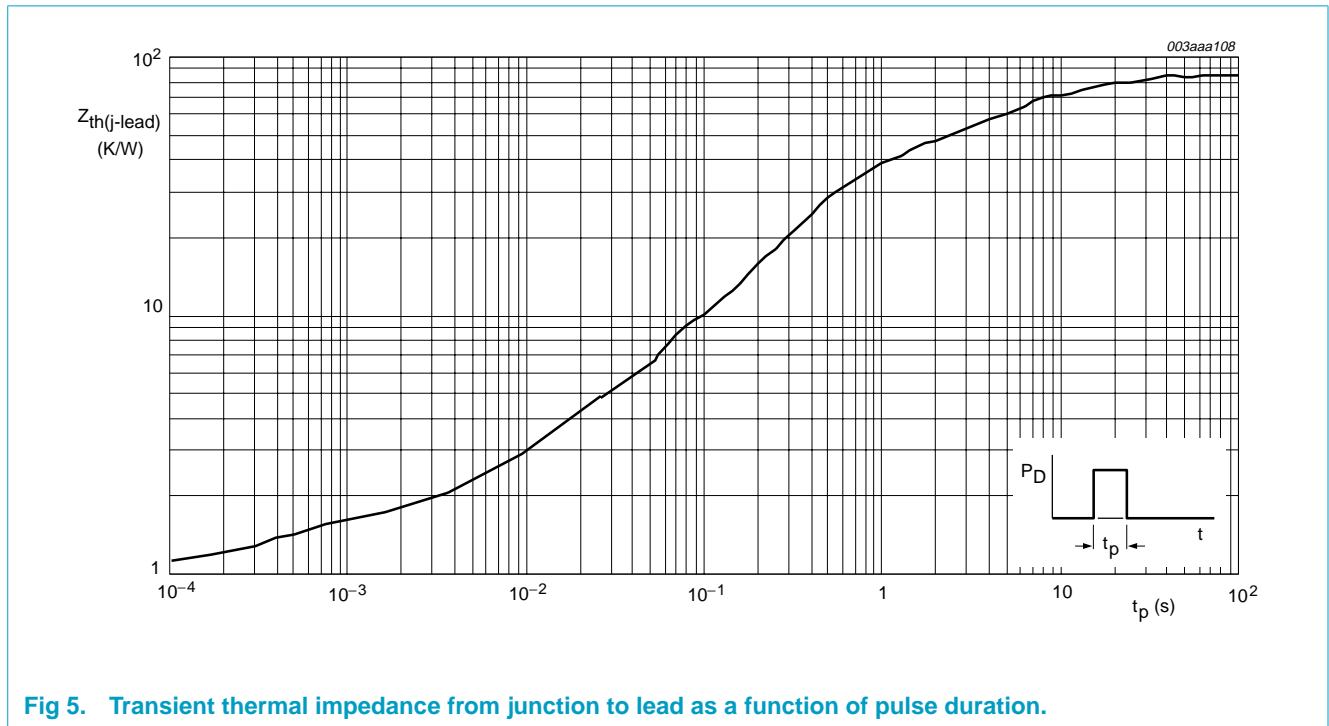


Fig 5. Transient thermal impedance from junction to lead as a function of pulse duration.

8. Characteristics

Table 5: Characteristics

$T_j = 25\text{ °C}$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Static characteristics						
I_{GT}	gate trigger current	$V_D = 12\text{ V}$; $I_T = 0.1\text{ A}$; gate open circuit	-	3	12	μA
I_L	latching current	$V_D = 12\text{ V}$; $I_{GT} = 0.5\text{ mA}$; $R_{GK} = 1\text{ k}\Omega$	-	2	6	mA
I_H	holding current		-	2	5	mA
V_T	on-state voltage	$I_T = 1.0\text{ A}$	-	1.2	1.35	V
V_{GT}	gate trigger voltage	$I_T = 10\text{ mA}$; gate open circuit				
		$V_D = 12\text{ V}$	-	0.5	0.8	V
		$V_D = V_{DRM(max)}$; $T_j = 125\text{ °C}$	0.2	0.3	-	V
I_D	off-state current	$V_D = V_{DRM(max)}$; $V_R = V_{RRM(max)}$;	-	50	100	μA
I_R	reverse current	$T_j = 125\text{ °C}$; $R_{GK} = 1\text{ k}\Omega$	-	50	100	μA
Dynamic characteristics						
dV_D/dt	rate of rise of off-state voltage	$V_D = 0.67 V_{DRM(max)}$; $T_{case} = 125\text{ °C}$; exponential waveform; $R_{GK} = 1\text{ k}\Omega$	-	25	-	$\text{V}/\mu\text{s}$
t_{gt}	gate controlled turn-on time	$I_{TM} = 2.0\text{ A}$; $V_D = V_{DRM(max)}$; $I_G = 10\text{ mA}$; $dI_G/dt = 0.1\text{ A}/\mu\text{s}$	-	2	-	μs
t_q	commutated turn-off time	$V_D = 0.67 V_{DRM(max)}$; $T_j = 125\text{ °C}$; $I_{TM} = 1.6\text{ A}$; $V_R = 35\text{ V}$; $dI_{TM}/dt = 30\text{ A}/\mu\text{s}$; $dV_D/dt = 2\text{ V}/\mu\text{s}$; $R_{GK} = 1\text{ k}\Omega$	-	100	-	μs

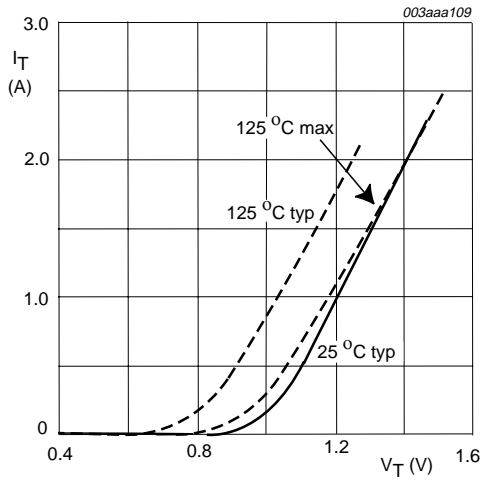
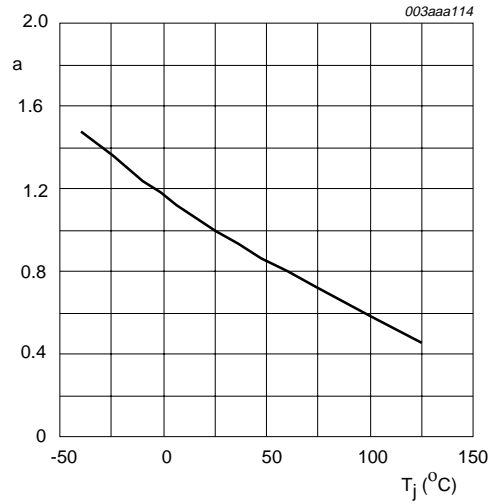
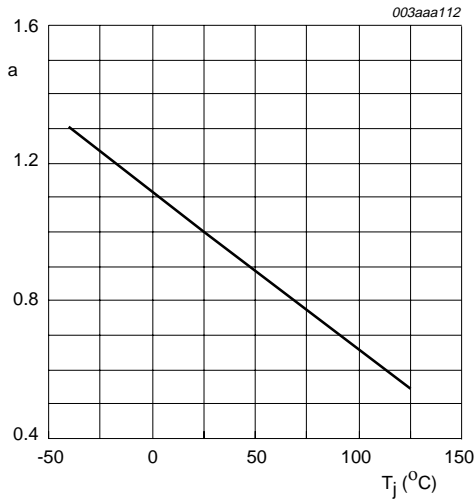


Fig 6. On-state current as a function of on-state voltage; typical and maximum values.



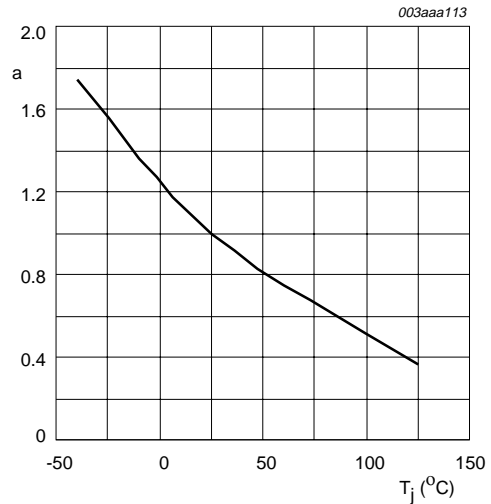
$$a = \frac{I_{L(T_j)}}{I_{L(25^\circ\text{C})}}$$

Fig 7. Normalized latching current as a function of junction temperature; typical values.



$$a = \frac{V_{GT(T_j)}}{V_{GT(25^\circ\text{C})}}$$

Fig 8. Normalized gate trigger voltage as a function of junction temperature; typical values.



$$a = \frac{I_{GT(T_j)}}{I_{GT(25^\circ\text{C})}}$$

Fig 9. Normalized gate trigger current as a function of junction temperature; typical values.

9. Package outline

Plastic single-ended leaded (through hole) package; 3 leads

SOT54

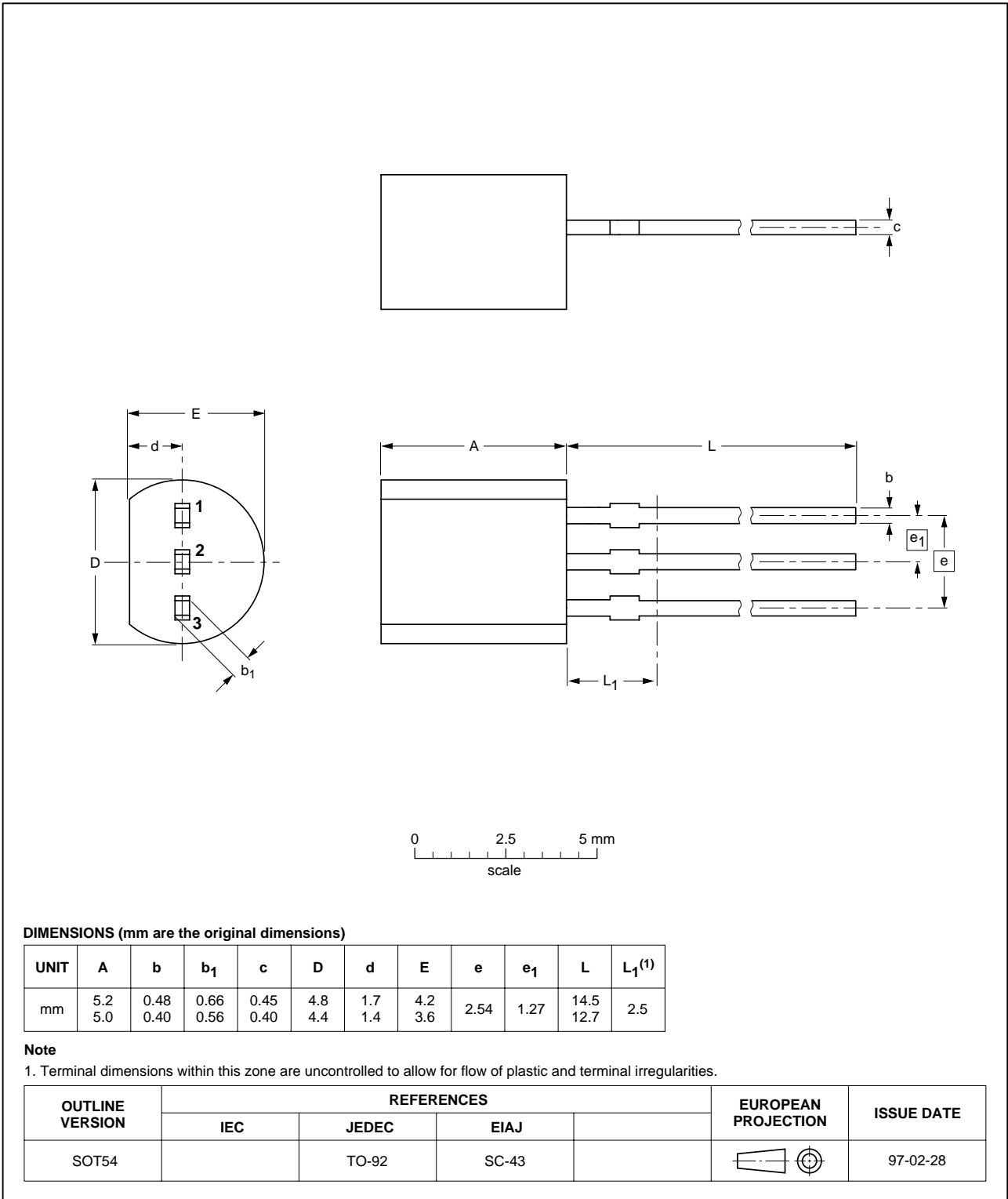


Fig 10. SOT54 (TO-92).

10. Revision history

Table 6: Revision history

Rev	Date	CPCN	Description
01	20011101	-	Product data; initial version

11. Data sheet status

Data sheet status ^[1]	Product status ^[2]	Definition
Objective data	Development	This data sheet contains data from the objective specification for product development. Philips Semiconductors reserves the right to change the specification in any manner without notice.
Preliminary data	Qualification	This data sheet contains data from the preliminary specification. Supplementary data will be published at a later date. Philips Semiconductors reserves the right to change the specification without notice, in order to improve the design and supply the best possible product.
Product data	Production	This data sheet contains data from the product specification. Philips Semiconductors reserves the right to make changes at any time in order to improve the design, manufacturing and supply. Changes will be communicated according to the Customer Product/Process Change Notification (CPCN) procedure SNW-SQ-650A.

[1] Please consult the most recently issued data sheet before initiating or completing a design.

[2] The product status of the device(s) described in this data sheet may have changed since this data sheet was published. The latest information is available on the Internet at URL <http://www.semiconductors.philips.com>.

12. Definitions

Short-form specification — The data in a short-form specification is extracted from a full data sheet with the same type number and title. For detailed information see the relevant data sheet or data handbook.

Limiting values definition — Limiting values given are in accordance with the Absolute Maximum Rating System (IEC 60134). Stress above one or more of the limiting values may cause permanent damage to the device. These are stress ratings only and operation of the device at these or at any other conditions above those given in the Characteristics sections of the specification is not implied. Exposure to limiting values for extended periods may affect device reliability.

Application information — Applications that are described herein for any of these products are for illustrative purposes only. Philips Semiconductors make no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

13. Disclaimers

Life support — These products are not designed for use in life support appliances, devices, or systems where malfunction of these products can reasonably be expected to result in personal injury. Philips Semiconductors customers using or selling these products for use in such applications do so at their own risk and agree to fully indemnify Philips Semiconductors for any damages resulting from such application.

Right to make changes — Philips Semiconductors reserves the right to make changes, without notice, in the products, including circuits, standard cells, and/or software, described or contained herein in order to improve design and/or performance. Philips Semiconductors assumes no responsibility or liability for the use of any of these products, conveys no licence or title under any patent, copyright, or mask work right to these products, and makes no representations or warranties that these products are free from patent, copyright, or mask work right infringement, unless otherwise specified.

Contact information

For additional information, please visit <http://www.semiconductors.philips.com>.
For sales office addresses, send e-mail to: sales.addresses@www.semiconductors.philips.com.

Fax: +31 40 27 24825

Contents

1	Description	2
2	Features	2
3	Applications	2
4	Pinning information	2
5	Quick reference data	2
6	Limiting values	3
7	Thermal characteristics	5
7.1	Transient thermal impedance	5
8	Characteristics	6
9	Package outline	8
10	Revision history	9
11	Data sheet status	10
12	Definitions	10
13	Disclaimers	10

© Koninklijke Philips Electronics N.V. 2001.
Printed in The Netherlands

All rights are reserved. Reproduction in whole or in part is prohibited without the prior written consent of the copyright owner.

The information presented in this document does not form part of any quotation or contract, is believed to be accurate and reliable and may be changed without notice. No liability will be accepted by the publisher for any consequence of its use. Publication thereof does not convey nor imply any license under patent- or other industrial or intellectual property rights.

Date of release: 1 November 2001

Document order number: 9397 750 08574



PHILIPS

Let's make things better.